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EDUCATION

- Ph.D. in Condensed Matter Physics, Johns Hopkins University, 2003–2008.
  Dissertation: *Magnetic Ordering in Frustrated Antiferromagnets on the Pyrochlore Lattice.*
- Ph.D. in Optoelectronics Engineering, National Taiwan University, 1996–2001.
  Dissertation: *Theoretical Modeling and Filter Design of Binary Waveguide Gratings.*
- B.S. in Electrical Engineering, National Taiwan University, 1992–1996.

PERSONAL Citizenship: Taiwan.

RESEARCH EXPERIENCE

- J. Robert Oppenheimer Fellow, Los Alamos National Laboratory, 2012-present.
- ICAM Postdoctoral Fellow, U. Wisconsin-Madison/Los Alamos National Lab, 2010-2012.
- Postdoctoral Research Associate, University of Wisconsin-Madison, 2008-2010.
- Research Assistant, Johns Hopkins University, 2003-2008.
- Research Assistant, National Taiwan University, 1996-2003.

PROFESSIONAL ACTIVITIES

- Visiting scientist, Max Planck Institute for Physics of Complex Systems, 2009–2013.
- Visiting scientist, Academia Sinica, Taipei, Taiwan, 2012, 2014.
- Visiting scientist, University of Florida, Gainesville, May 2002.

FELLOWSHIPS AND AWARDS

- Postdoctoral Distinguished Performance Awards, Los Alamos National Laboratory, 2014.
- J. Robert Oppenheimer Fellowship, LANL 2012.
- Institute for Complex Adaptive Matter (ICAM) Postdoctoral Fellowship, 2010-2012.
- Krieger School of Arts and Sciences Teaching Award finalist, Johns Hopkins University, 2004.
- Donald E. Kerr and Barbara Stanley Fellowship, Johns Hopkins University, 2003–2004.
- Presidential Award, National Taiwan University, 1993.

OTHER EXPERIENCE

- Technical Consultant at *Infomax Optical Technology Corporation*, http://www.opto-infomax.com.tw, Hsinchu City, Taiwan, 2001.
- Co-founder and Programming Engineer of *Eki Digital Technology Corporation*, http://www.eki.com.tw, Taipei, Taiwan, 1997.

PATENTS

- U.S. Patent Number: 6734976, *Method and system for measuring an ultrashort optical pulse*, 2004.

PROFESSIONAL MEMBERSHIP

- American Physical Society, Optical Society of America.